

ISSUE DATE

PATENT NUMBER and

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER		
10099988	03/19/2002	714	584	2133	' Knamen		
**APPLICANT Masahiro;	15 N N N N	- 714 - Atsuo; Yo	shino Toshital		nano Tetsutsugu; Sudura		
BEST AVAILABLE COPY ** FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-086267 03/23/2001							
	NOT PUBLISH			ND L	ATTORNEY DOCKET NO		
35 USC 119 conditions met □ yes □ no Verified and Acknowledged Examiners's initials T2171.0201/P201							
TITLE: Manufacture of probe unit having lead probes extending beyong edge of substrate US.DEPT. OF COMM./PAT.& TMPTO-436L(Rev. 12-94)							
			<u> </u>	10.1			

NOTICE OF ALLOY	WANCE MAILED		CLAIMS ALLOWED
		Assistant Examiner	Total Claims Print Claim for O.G
ISSU	E FEE	1. 2 x 12 - 1 25 - 1 2 3 3 2 3 3 3	DRAWING AND
Amount Due	Date Paid		Sheets Drwg. Figs.Drwg. Print Fig.
. i, .		Primary Examiner	
TERMINAL		PREPARED FOR ISSUE	Applicati n Examiner
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